

## Crystal Orientation Dependence of X-ray Magnetic Linear Dichroism in Altermagnetic RuO<sub>2</sub>

Jun Okabayashi,<sup>1\*</sup> Zhenchao Wen,<sup>2</sup> Yoshio Miura,<sup>3,2</sup> Hiroaki Sukegawa,<sup>2</sup> and Seiji Mitani<sup>2</sup>

<sup>1</sup>Research Center for Spectrochemistry, The University of Tokyo, Bunkyo-ku, Tokyo 113-0033, Japan

<sup>2</sup>Research Center for Magnetic and Spintronic Materials, National Institute for Materials Science (NIMS), Tsukuba, Ibaraki 305-0047, Japan

<sup>3</sup>Kyoto Institute of Technology, Kyoto 606-8585, Japan

\*E-mail: jun@chem.s.u-tokyo.ac.jp

Altermagnetism has recently been developed using time-reversal symmetry breaking spintronics and spin-splitting phenomena in materials with collinear-compensated magnetic order [1]. It arises from the unique band structures that split up and down spin bands, which differs from ferromagnetic exchange splitting and antiferromagnetic compensation. Some materials, such as RuO<sub>2</sub>, MnTe, and CrSb, have been classified as exhibiting altermagnetism. In particular, RuO<sub>2</sub> features unique spin-dependent elliptical Fermi surfaces, which are regarded as the origin of the spin-splitting effect [2]. However, a recent topical issue regarding altermagnetism in RuO<sub>2</sub> is the existence or absence of magnetic moments at the Ru sites. Although recent  $\mu$ SR measurements for bulk RuO<sub>2</sub> reported the absence of magnetic moments [3], the RuO<sub>2</sub> film includes local strain, which might be essential for the presence of finite Ru magnetic moments and altermagnetic properties. To address these controversial issues, we employ x-ray magnetic linear dichroism (XMLD), which probes the square of the magnetization. The x-ray magnetic circular dichroism (XMCD) is ineffective for detecting compensated spins. Thus far, we have examined the angular-dependent XMLD for RuO<sub>2</sub> (101) to determine the Néel vector direction along [001] with finite magnetic moments at each Ru site [4]. In this presentation, to further understand the details of the magnetic structures of RuO<sub>2</sub>, we performed XMLD for other (110) orientation planes.

We prepared a sample of a 20-nm-thick rutile-type RuO<sub>2</sub> (101) layer and a RuO<sub>2</sub> (110) layer, both conductive, grown on single-crystal Al<sub>2</sub>O<sub>3</sub>(1 $\bar{1}$ 02) substrates and TiO<sub>2</sub> (110) substrates, respectively, using reactive rf-sputtering. The Néel temperature of the sample was determined to be approximately 400 K. The magnetic moments in RuO<sub>2</sub> are aligned along the [001] direction. The direction of the Néel vector was established from previous angular-dependent XMLD measurements [4]. XMCD and XMLD measurements for the Ru *M*-edge were conducted at BL-7A and BL-16A in the Photon Factory (KEK). The total-electron-yield mode was employed at 80 K. For the XMLD, horizontally and vertically linearly polarized beams were directed into the sample, and the difference is defined as linear dichroism.

The x-ray absorption spectra in the 4*d* transition-metal element *M*-edge consist of not only 3*p* to 4*d* transitions but also 3*p* to 5*s* transition peaks. There was no XMCD signal due to complete compensation in the total magnetization (*M*). To detect *M*<sup>2</sup>, XMLD was performed with strong coupling geometry between the electric field in the incident beam and the Néel vector in the sample. For the RuO<sub>2</sub> (110) plane, the Néel vector aligns along the in-plane [001] direction. XMLD signals are clearly detected, and by rotating the sample position in the plane, the sign of XMLD changes, suggesting a change in the Néel vector. These observations indicate that the magnetic moments at the Ru sites align along the Néel vector. *M*<sup>2</sup> intensities are nearly identical to those of RuO<sub>2</sub> (101), suggesting that finite magnetic moments can form for both orientations.

This work was partly supported by JSPS KAKENHI No. JP22H04966.

**References:** [1] L. Šmejkal *et al.*, [Phys. Rev. X](#) **12**, 040501 (2022). [2] S. Karube *et al.*, [Phys. Rev. Lett.](#) **129**, 137201 (2022).

[3] M. Hiraiishi *et al.*, [Phys. Rev. Lett.](#) **132**, 166702 (2024). [4] C. He, Z. Wen, J. Okabayashi *et al.*, submitted.